Notice of References Cited

Ī	Application/Control No.	Applicant(s)/Pater	nt Under
	10/539,975	Reexamination DE VAAN ET AL.	
	Examiner	Art Unit	
	PAULOS M. NATNAEL	2622	Page 1 of 1

U.S. PATENT DOCUMENTS

T.		Document Number	Date		
*		Country Code-Number-Kind Code	MM-YYYY	Name	Classification
*	Α	US-6,042,236	03-2000	Hatakeyama et al.	353/31
*	В	US-6,454,440	09-2002	Yamamoto, Chikara	362/293
*	С	US-6,626,540	09-2003	Ouchi et al.	353/31
*	D	US-5,808,759	09-1998	Okamori et al.	359/15
*	Е	US-5,754,260	05-1998	Ooi et al.	349/10
*	F	US-6,862,047	03-2005	Hibi, Taketoshi	348/743
*	G	US-5,854,707	12-1998	Kasama et al.	359/487
*	Н	US-5,661,608	08-1997	Barbier et al.	359/800
*	1	US-5,648,860	07-1997	Ooi et al.	349/10
	J	US-			
	К	US-			
	٦	US-			
	м	US-			

FOREIGN PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS						
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON DATENT DOCUMENTS

NON-PATENT DOCUMENTS		
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	×	

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.